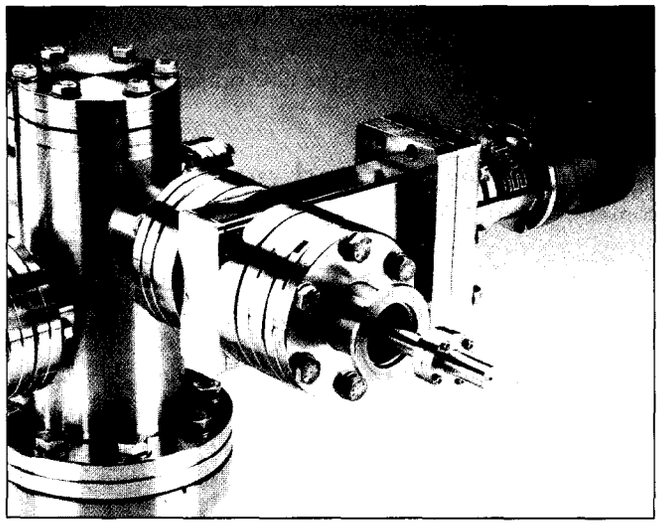
Hiden product launches

The **HPR-60** is a MBE gas sampling system designed for analysis of high pressure reaction processes, such as gas kinetics, plasmas, etc., up to 100 mbar (or up to 1 bar with optional third stage). The system is based on the Hiden triple filter quad mass spec with mass range options up to 2500 amu with sub-ppm detection and enhanced abundance sensitivity. The standard unit has a 2-stage inlet system with turbo pump for high pressure molecular beam sampling. Axially aligned orifices offer minimum disturbance of ion and radical species making the system suitable for large molecule clusters such as fullerenes, etc.



The Hiden HPR30 vacuum process sampling system.

Designed for "hands free" operation the **HPR30** process sampling system works over a pressure range of 10^{-1} to 10^{-4} mbar. The system combines a high performance quadropole mass spectrometer, differential pumping system and contamination resistant orifice for ppb detection of process contaminants and reaction products. The system also includes pneumatic valves and valve sequencer control module providing for automatic operation at both the process pressure and system base pressure along with analysis of pump down profiles.

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Microscope link for fluoroscence spectrophotometer

A new accessory is now available from Hitachi Scientific Instruments, which allows the F-2000 rapid scanning fluorescence spectrophotometer to be optically coupled directly to commercial fluorescence microscopes. In this way, spectral analyses can be made from small areas on the sample.

This powerful combination greatly extends the capability of the microscope by using standard equipment without the need for expensive, dedicated instrumentation. The technique is suitable for a wide range of applications including semiconductor quality control, where non-destructive techniques are of great importance.

The F-2000 features a high quality optical system. The use of large aperture stigmatic concave diffraction grating monochromator on the emission side ensures excellent signal to noise. Quantitative detection limits and minimum detectable areas will vary according to excitation conditions and optics of the particular microscope used. The full analysis facilities of the F-2000 can be used, including background corrections and quantitative measurements, where appropriate.

A scanning speed of 12 000 nm/minute means that the full wavelength range of 220-800 nm can be scanned in less than 3 seconds.

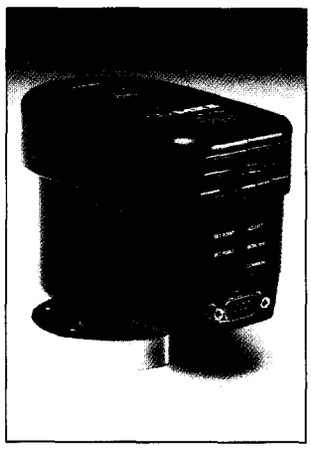
The high sensitivity of the F-2000 ensures that the performance of the spectrophotometer is not comprised when fast scanning speeds are used.

Contact: Vince Phelan, Hitachi Scientific Instruments, 7 Ivanhoe Road, Hogwood Industrial Estate, Finchampstead, Wokingham, Berkshire, RG40 4QQ, UK. Tel/fax: +44 (0) 118 932 8632/973 2622.

New high vacuum gauge system

MKS Instruments have introduced a new Inverted Magnetron Gauge Head. The series 903 Cold Cathode Sensor has close coupled electronics to give the transducer an extremely compact design.

The 903 Cold Cathode system can measure vacuum pressures from 10^{-3} to 10^{-10} Torr and has both an analogue output and a setpoint, with LED indicator as standard. These features allow the transducer to be used



as a system control element, relay gauge, alarm or remote sensors. A high voltage disable feature switches the sensor off when out of measurement range. The maximum bake-out temperature for the transducer is 400°C.

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0961-1290/97/$17.00